STM32L496xx STM32L4A6xx
Errata sheet

STM32L496xx and STM32L4A6xx device limitations

Applicability

This document applies to the part numbers of STM32L496xx and STM32L4A6xx devices listed in *Table 1* and their variants shown in *Table 2*.

Section 1 gives a summary and *Section 2* a description of device limitations, with respect to the device datasheet and reference manual RM0351.

Table 1. Device summary

Reference	Part numbers
STM32L496xx	STM32L496AE, STM32L496AG, STM32L496QE, STM32L496QG, STM32L496RE, STM32L496RG, STM32L496VE, STM32L496VG, STM32L496ZE, STM32L496ZG
STM32L4A6xx	STM32L4A6AG, STM32L4A6QG, STM32L4A6RG, STM32L4A6VG, STM32L4A6ZG

Table 2. Device variants

Reference	Silicon revision codes	
	Device marking[1]	REV_ID[2]
STM32L496xx STM32L4A6xx	B	0x2000

1. Refer to the device data sheet for how to identify this code on different types of package.

2. REV_ID[15:0] bit field of DBGMCU_IDCODE register. Refer to the reference manual.

Contents

1   Summary of device limitations

The following table gives a quick references to all documented device limitations of STM32L496xx and STM32L4A6xx and their status:

A = workaround available

N = no workaround available

P = partial workaround available

Applicability of a workaround may depend on specific conditions of target application. Adoption of a workaround may cause restrictions to target application. Workaround for a limitation is deemed partial if it only reduces the rate of occurrence and/or consequences of the limitation, or if it is fully effective for only a subset of instances on the device or in only a subset of operating modes, of the function concerned.

Table 3. Summary of device limitations

Function	Section	Limitation	Status
			Rev. B
Core	2.1.1	*Interrupted loads to SP can cause erroneous behavior*	A
	2.1.2	*VDIV or VSQRT instructions might not complete correctly when very short ISRs are used*	A
	2.1.3	*Store immediate overlapping exception return operation might vector to incorrect interrupt*	A
System	2.2.1	*Dual-bank boot not working in RDP Level 1 when the boot in Flash memory is selected by BOOT0 pin*	A
	2.2.2	*PCPROP area within a single Flash memory page becomes unprotected at RDP change from Level 1 to Level 0*	A
	2.2.3	*Data cache might be corrupted during Flash memory read-while-write operation*	A
	2.2.4	*MSI frequency overshoot upon Stop mode exit*	A
	2.2.5	*Internal voltage reference corrupted upon Stop mode entry with temperature sensing enabled*	A
	2.2.6	*V_{DDA} overconsumption under specific condition on PA3 or PB0*	N
	2.2.7	*Spurious brown-out reset after short run sequence*	A
	2.2.8	*Full JTAG configuration without NJTRST pin cannot be used*	A
FW	2.3.1	*Code segment unprotected if non-volatile data segment length is zero*	A
	2.3.2	*Code and non-volatile data unprotected upon bank swap*	A
FMC	2.4.1	*Dummy read cycles inserted when reading synchronous memories*	N
QUADSPI	2.5.1	*Wrong data can be read in memory-mapped after an indirect mode operation*	A
	2.5.2	*First nibble of data is not written after dummy phase*	A
ADC	2.6.1	*Wrong ADC result if conversion done late after calibration or previous conversion*	N

Table 3. Summary of device limitations (continued)

Function	Section	Limitation	Status
			Rev. B
TEMP	*2.7.1*	*Spurious temperature measurement due to spike noise*	A
COMP	*2.8.1*	*Comparator outputs cannot be configured in open-drain*	N
TSC	*2.9.1*	*Inhibited acquisition in short transfer phase configuration*	A
AES[1]	*2.10.1*	*Wrong TAG generation in GCM mode with encryption, for payloads smaller than 128 bits*	A
TIM	*2.11.1*	*HSE/32 is not available for TIM16 input capture if RTC clock is disabled or other than HSE*	A
LPTIM	*2.12.1*	*LPTIM1 outputs cannot be configured as open-drain*	N
	2.12.2	*MCU may remain stuck in LPTIM interrupt when entering Stop mode*	N
I2C	*2.13.1*	*10-bit master mode: new transfer cannot be launched if first part of the address is not acknowledged by the slave*	A
	2.13.2	*Wrong behavior in Stop mode when wakeup from Stop mode is disabled in I2C*	A
	2.13.3	*Wrong data sampling when data setup time ($t_{SU;DAT}$) is shorter than one I2C kernel clock period*	P
	2.13.4	*Spurious bus error detection in master mode*	A
	2.13.5	*Last-received byte loss in reload mode*	P
USART	*2.14.1*	*nRTS is active while RE = 0 or UE = 0*	A
LPUART	*2.15.1*	*LPUART1 outputs cannot be configured as open-drain*	N
SPI	*2.16.1*	*BSY bit may stay high at the end of data transfer in slave mode*	A
	2.16.2	*Wrong CRC in full-duplex mode handled by DMA with imbalanced setting of data counters*	A
SDMMC	*2.17.1*	*MMC stream write of less than 7 bytes does not work correctly*	A
bxCAN	*2.18.1*	*bxCAN Time-triggered mode not supported*	N
OTG_FS	*2.19.1*	*Data FIFO gets corrupted if the write sequence to the Transmit FIFO is interleaved with other OTGFS register access*	A

1. Only applicable to STM32L4A6xx

2 Description of device limitations

The following sections describe limitations of the applicable devices with Arm® core and provide workarounds if available. They are grouped by device functions.

2.1 Core

Errata notice for the Arm® Cortex®-M4F core revisions r0 is available from http://infocenter.arm.com. Only applicable information from the Arm errata notice is replicated in this document. Extra information may be added for more clarity.

2.1.1 Interrupted loads to SP can cause erroneous behavior

This limitation is registered under Arm ID number 752770 and classified into "Category B". Its impact to the device is minor.

Description

If an interrupt occurs during the data-phase of a single word load to the stack-pointer (SP/R13), erroneous behavior can occur. In all cases, returning from the interrupt will result in the load instruction being executed an additional time. For all instructions performing an update to the base register, the base register will be erroneously updated on each execution, resulting in the stack-pointer being loaded from an incorrect memory location.

The affected instructions that can result in the load transaction being repeated are:

- LDR SP, [Rn],#imm
- LDR SP, [Rn,#imm]!
- LDR SP, [Rn,#imm]
- LDR SP, [Rn]
- LDR SP, [Rn,Rm]

The affected instructions that can result in the stack-pointer being loaded from an incorrect memory address are:

- LDR SP,[Rn],#imm
- LDR SP,[Rn,#imm]!

As compilers do not generate these particular instructions, the limitation is only likely to occur with hand-written assembly code.

Workaround

Both issues may be worked around by replacing the direct load to the stack-pointer, with an intermediate load to a general-purpose register followed by a move to the stack-pointer.

Example:

Replace LDR SP,[R0] with:

```
LDR R2,[R0]
MOV SP,R2
```

2.1.2 VDIV or VSQRT instructions might not complete correctly when very short ISRs are used

This limitation is registered under Arm ID number 776924 and classified into "Category B". Its impact to the device is limited.

Description

The VDIV and VSQRT instructions take 14 cycles to execute. When an interrupt is taken a VDIV or VSQRT instruction is not terminated, and completes its execution while the interrupt stacking occurs. If lazy context save of floating point state is enabled then the automatic stacking of the floating point context does not occur until a floating point instruction is executed inside the interrupt service routine.

Lazy context save is enabled by default. When it is enabled, the minimum time for the first instruction in the interrupt service routine to start executing is 12 cycles. In certain timing conditions, and if there is only one or two instructions inside the interrupt service routine, then the VDIV or VSQRT instruction might not write its result to the register bank or to the FPSCR.

The failure occurs when the following condition is met:

1. The floating point unit is enabled
2. Lazy context saving is not disabled
3. A VDIV or VSQRT is executed
4. The destination register for the VDIV or VSQRT is one of s0 - s15
5. An interrupt occurs and is taken
6. The interrupt service routine being executed does not contain a floating point instruction
7. Within 14 cycles after the VDIV or VSQRT is executed, an interrupt return is executed

A minimum of 12 of these 14 cycles are utilized for the context state stacking, which leaves 2 cycles for instructions inside the interrupt service routine, or 2 wait states applied to the entire stacking sequence (which means that it is not a constant wait state for every access).

In general, this means that if the memory system inserts wait states for stack transactions (that is, external memory is used for stack data), then this erratum cannot be observed.

The effect of this erratum is that the VDIV or VQSRT instruction does not complete correctly and the register bank and FPSCR are not updated, which means that these registers hold incorrect, out of date, data.

Workaround

A workaround is only required if the floating point unit is enabled. A workaround is not required if the stack is in external memory.

There are two possible workarounds:

- Disable lazy context save of floating point state by clearing LSPEN to 0 (bit 30 of the FPCCR at address 0xE000EF34).
- Ensure that every interrupt service routine contains more than 2 instructions in addition to the exception return instruction.

2.1.3 Store immediate overlapping exception return operation might vector to incorrect interrupt

This limitation is registered under Arm ID number 838869 and classified into "Category B (rare)". Its impact to the device is minor.

Description

The core includes a write buffer that permits execution to continue while a store is waiting on the bus. Under specific timing conditions, during an exception return while this buffer is still in use by a store instruction, a late change in selection of the next interrupt to be taken might result in there being a mismatch between the interrupt acknowledged by the interrupt controller and the vector fetched by the processor.

The failure occurs when the following condition is met:

1. The handler for interrupt A is being executed.
2. Interrupt B, of the same or lower priority than interrupt A, is pending.
3. A store with immediate offset instruction is executed to a bufferable location.
   – STR/STRH/STRB <Rt>, [<Rn>,#imm]
   – STR/STRH/STRB <Rt>, [<Rn>,#imm]!
   – STR/STRH/STRB <Rt>, [<Rn>],#imm
4. Any number of additional data-processing instructions can be executed.
5. A BX instruction is executed that causes an exception return.
6. The store data has wait states applied to it such that the data is accepted at least two cycles after the BX is executed.
   – Minimally, this is two cycles if the store and the BX instruction have no additional instructions between them.
   – The number of wait states required to observe this erratum needs to be increased by the number of cycles between the store and the interrupt service routine exit instruction.
7. Before the bus accepts the buffered store data, another interrupt C is asserted which has the same or lower priority as A, but a greater priority than B.

Example:

The processor should execute interrupt handler C, and on completion of handler C should execute the handler for B. If the conditions above are met, then this erratum results in the processor erroneously clearing the pending state of interrupt C, and then executing the handler for B twice. The first time the handler for B is executed it will be at interrupt C's priority level. If interrupt C is pended by a level-based interrupt which is cleared by C's handler then interrupt C will be pended again once the handler for B has completed and the handler for C will be executed.

As the STM32 interrupt C is level based, it eventually becomes pending again and is subsequently handled.

Workaround

For software not using the memory protection unit, this erratum can be worked around by setting DISDEFWBUF in the Auxiliary Control Register.

In all other cases, the erratum can be avoided by ensuring a DSB occurs between the store and the BX instruction. For exception handlers written in C, this can be achieved by

inserting the appropriate set of intrinsics or inline assembly just before the end of the interrupt function, for example:

ARMCC:

```
...
__schedule_barrier();
__asm{DSB};
__schedule_barrier();
}
```

GCC:

```
...
__asm volatile ("dsb 0xf":::"memory");
}
```

2.2 System

2.2.1 Dual-bank boot not working in RDP Level 1 when the boot in Flash memory is selected by BOOT0 pin

Description

When the read protection (RDP) is in Level 1, the nSWBoot0 option bit is set and the BOOT0 pin level is low, the dual-bank boot does not work (BFB2 option bit = 1).

The user code is only executed when BANK 0 is valid.

Workaround

Do not rely on the BOOT0 pin to select the boot in Flash memory. Instead, use the option bytes for that purpose, setting the nSWBoot0 option bit to 0, the nBOOT0 option bit to 1, and the BFB2 option bit to 1. This setting allows the correct check of the address 0 of the two memory banks, in order to execute from the correct one.

2.2.2 PCPROP area within a single Flash memory page becomes unprotected at RDP change from Level 1 to Level 0

Description

With PCROP_RDP option bit cleared, the change of RDP from Level 1 to Level 0 normally results in erasure of Flash memory banks except the Flash memory pages containing the PCROP area. The PCROP area remains read-protected.

This operates as expected if the PCROP area crosses the limits of at least one Flash memory page, which is always true if PCROP area size exceeds 2 Kbytes. The limitation occurs if the PCROP area is fully contained within one single Flash memory page. Upon the RDP change from Level 1 to Level 0, the Flash memory bank with PCROP area is not erased and the read protection of the PCROP area is removed.

Workaround

Always define PCROP area such that it crosses limits of at least one Flash memory page.

2.2.3 Data cache might be corrupted during Flash memory read-while-write operation

Description

When a write to the internal Flash memory is done, the data cache is normally updated to reflect the data value update. During this data cache update, a read to the other Flash memory bank may occur; this read can corrupt the data cache content and subsequent read operations at the same address (cache hits) will be corrupted.

This limitation only occurs in dual bank mode, when reading (data access or code execution) from one bank while writing to the other bank with data cache enabled.

Workaround

When the application is performing data accesses in both Flash memory banks, the data cache must be disabled by resetting the DCEN bit before any write to the Flash memory. Before enabling the data cache again, it must be reset by setting and then resetting the DCRST bit.

Code Example

```
  /* Disable data cache  */
  __HAL_FLASH_DATA_CACHE_DISABLE();

  /* Set PG bit */
  SET_BIT(FLASH->CR, FLASH_CR_PG);

  /* Program the Flash word */
WriteFlash(Address, Data);

  /* Reset data cache */
  __HAL_FLASH_DATA_CACHE_RESET();
  /* Enable data cache */
  __HAL_FLASH_DATA_CACHE_ENABLE();
```

2.2.4 MSI frequency overshoot upon Stop mode exit

Description

When
- the system is clocked by the MSI clock, and
- MSI is selected as system clock source upon wakeup from Stop mode, and
- a wakeup event occurs only a few system clock cycles before entering Stop mode,

then upon the exit from Stop mode, the MSI frequency can overshoot above its selected range.

The limitation applies to all Stop modes: Stop 0, Stop 1 and Stop 2.

Workaround

Apply the following sequence:

1. Select HSI16 as system clock.

2. Shut MSI down.

3. Wait for MSIRDY to go low (after 6 MSI clock cycles).

4. Mask interrupts by setting PRIMASK (in the core).

5. Initiate Stop mode entry, with MSI selected as system clock source upon wakeup. At this point, the systems enters Stop mode (unless an early wakeup event occurs). The following steps are done upon Stop mode exit.

6. Enable MSI.

7. Wait for MSIRDY to go high.

8. Select MSI as system clock.

9. Unmask interrupts by clearing PRIMASK.

The steps 6 through 8 are required to cover the case of the MCU not entering Stop mode after the step 5 (due to an early wakeup event), thus maintaining HSI16 as system clock.

This workaround guarantees the best wakeup time.

2.2.5 Internal voltage reference corrupted upon Stop mode entry with temperature sensing enabled

Description

When entering Stop mode with the temperature sensor channel and the associated ADC(s) enabled, the internal voltage reference may be corrupted.

The occurrence of the corruption depends on the supply voltage and the temperature.

The corruption of the internal voltage reference may cause:

- an overvoltage in V_{CORE} domain
- an overshoot / undershoot of internal clock (LSI, HSI, MSI) frequencies
- a spurious brown-out reset

The limitation applies to Stop 1 and Stop 2 modes.

Workaround

Before entering Stop mode

- disable the ADC(s) using the temperature sensor signal as input, and/or
- disable the temperature sensor channel, by clearing the CH17SEL bit of the ADCx_CCR register.

Disabling both allows consuming less power during Stop mode.

2.2.6   V$_{DDA}$ overconsumption under specific condition on PA3 or PB0

Description

An overconsumption can appear on V$_{DDA}$ when all the following conditions are met at the same time:

- A voltage V$_{PAD}$ is applied on PA3 or PB0 with
  (V$_{DDA}$ + 50 mV) < V$_{PAD}$ < (V$_{DDA}$ + 600 mV)
- The OPAMP output is not used (OPAMPx_VOUT pins are not driven by the OPAMP)
- Temperature is below 0 °C

This extra consumption is constant and can reach up to 1 mA.

Workaround

None except avoiding the previous conditions.

2.2.7   Spurious brown-out reset after short run sequence

Description

When the MCU wakes up from Stop mode and enters the Stop mode again within a short period of time, a spurious brown-out reset may be generated.

This limitation depends on the supply voltage (see *Table 4*).

Table 4. Minimum run time

V$_{DD}$ supply voltage (V)	Minimum run time (µs)
1.71	15
1.8	13
2.0	11
2.2	9
2.4	8
2.6	6
2.8	5
3.0	3
3.2 and above	2

The minimum run time defined in the previous table corresponds to the firmware execution time on the core. There is no need to add a delay for the wakeup time. Note also that the MCO output length is longer than the firmware execution time.

This limitation applies to Stop 1 and Stop 2 modes.

Workaround

Ensure that the run time between exiting Stop mode and entering Stop mode again is long enough not to generate a brown-out reset. This can be done by adding a software loop or

using a timer to add a delay; the system clock frequency can be reduced during this waiting loop in order to minimize power consumption.

2.2.8 Full JTAG configuration without NJTRST pin cannot be used

Description

When using the JTAG debug port in Debug mode, the connection with the debugger is lost if the NJTRST pin (PB4) is used as a GPIO. Only the 4-wire JTAG port configuration is impacted.

Workaround

Use the SWD debug port instead of the full 4-wire JTAG port.

2.3 FW

2.3.1 Code segment unprotected if non-volatile data segment length is zero

Description

If during FW configuration the length of firewall-protected non-volatile data segment is set to zero through the LENG[21:8] bitfield of the FW_NVDSL register, the firewall protection of code segment does not operate.

Workaround

Always set the LENG[21:8] bitfield of the FW_NVDSL register to a non-zero value, even if no firewall protection of data in the non-volatile data segment is required.

2.3.2 Code and non-volatile data unprotected upon bank swap

Description

With firewall-protected code and non-volatile data segments located in the same Flash memory bank, both segments become unprotected (available to illegal access) upon Flash memory bank swap by software.

Workaround

Map the firewall-protected code segment in one Flash memory bank and the non-volatile data segment in another Flash memory bank in a symmetric way (same relative address and same length).

2.4 FMC

2.4.1 Dummy read cycles inserted when reading synchronous memories

Description

When performing a burst read access to a synchronous memory, two dummy read accesses are performed at the end of the burst cycle whatever the type of AHB burst access.

However, the extra data values which are read are not used by the FMC and there is no functional failure.

Workaround

None.

2.5 QUADSPI

2.5.1 Wrong data can be read in memory-mapped after an indirect mode operation

Description

Wrong data can be read with the first memory-mapped read request when in the following condition:

- Quad-SPI peripheral entered memory-mapped mode with both LSB bits in the address register QUADSPI_AR[1:0] not reset.

Workaround

QUADSPI_AR register must be reset just before entering memory-mapped mode.

Depending on the current Quad-SPI operating mode, one of the two workarounds listed below can be used:

1. Indirect read mode: reset address register then do an abort request to stop reading and clear busy bit.
   Then enter to memory-mapped mode.
2. Indirect write mode: reset the address register then enter to memory-mapped mode

User should take care to not write to QUADSPI_DR register after resetting address register.

2.5.2 First nibble of data is not written after dummy phase

Description

The first nibble of data to be written to the external Flash memory is lost in the following conditions:

- QUADSPI is used in indirect write mode
- And at least one dummy cycle is used

Workaround

Use alternate bytes instead of dummy phase to add latency between address phase and data phase. Instead, use alternate bytes to substitute the dummy cycles. The same latency can be achieved if the number of dummy cycles to substitute with alternate-byte cycles is an integer multiple of the number of cycles required for transferring one alternate byte, as shown in the table:

QUADSPI mode	Number of cycles per alternate byte
4-data-line DDR	1
4-data-line SDR	2
2-data-line SDR	3
2-data-line SDR	4

For example, the latency corresponding to eight dummy cycles can be exactly substituted with one single alternate byte in 1-data-line SDR mode, but two alternate bytes are required in 2-data-line SDR mode. One single dummy cycle can only exactly be substituted in 4-data-line DDR mode, using one alternate byte.

Note: *This is also applicable to dual-flash memory mode.*

2.6   ADC

2.6.1   Wrong ADC result if conversion done late after calibration or previous conversion

Description

The result of an ADC conversion done more than 1 ms later than the previous ADC conversion or ADC calibration might be incorrect.

Workaround

Perform two consecutive ADC conversions in single, scan or continuous mode. Reject the result of the first conversion and only keep the result of the second.

2.7   TEMP

Die461_17

2.7.1   Spurious temperature measurement due to spike noise

Description

Depending on the MCU activity, internal interference may cause temperature-dependent spike noise on the temperature sensor output to the ADC, resulting in occasional spurious (outlying) temperature measurement.

Workaround

Perform a series of measurements and process the acquired data samples such as to obtain a mean value not affected by the outlying samples.

For this, it is recommended to use interquartile mean (IQM) algorithm with at least 64 samples. IQM is based on rejecting the quarters (quartiles) of sample population with the

lowest and highest values and on computing the mean value only using the remaining (interquartile) samples.

The acquired sample values are first sorted from lowest to highest, then the sample sequence is truncated by removing the lowest and highest sample quartiles.

Example:

Data	Sample												Mean
	1	**2**	**3**	**4**	**5**	**6**	**7**	**8**	**9**	**10**	**11**	**12**	
Acquired	17.2	10.92	9.56	2.12	9.82	10.72	10.6	3.5	9.46	9.78	9.5	1.1	8.69
Sorted	1.1	2.12	3.5	9.46	9.5	9.56	9.78	9.82	10.6	10.72	10.92	17.2	8.69
Truncated	-	-	-	9.46	9.5	9.56	9.78	9.82	10.6	-	-	-	9.79

The measurement result after the IQM post-processing in the example is 9.79. For consistent results, use a minimum of 64 samples. It is recommended to optimize the code performing the sort task such as to minimize its processing power requirements.

2.8   COMP

2.8.1   Comparator outputs cannot be configured in open-drain

Description

Comparator outputs are always forced in push-pull mode whatever the GPIO output type configuration bit value.

Workaround

None.

2.9   TSC

2.9.1   Inhibited acquisition in short transfer phase configuration

Description

The input buffer of the I/O is normally masked outside the transfer window time then sampled twice before being checked for acquisition. Such check is normally performed on the last TSC clock cycle of the transfer of charge phase. When the transfer of charge duration is less than three cycles the acquisition is inhibited.

Workaround

The following configurations are forbidden:

1.   The PGPSC[2:0] field set to 000 and the CTPL[3:0] field to 0000 or 0001
2.   The PGPSC[2:0] field set to 111 and the CTPL[3:0] field to 0000

2.10 AES

2.10.1 Wrong TAG generation in GCM mode with encryption, for payloads smaller than 128 bits

Description

When the AES is configured in GCM mode with encryption, the TAG generation is wrong during the Final phase if the size of the last plain text block of the payload is lower than 128 bits.

Workaround

During payload phase and before inserting a last payload block smaller than 128 bits, pursue the following steps:

- Switch the AES mode to CTR mode by writing the bitfield CHMOD[2:0] = 010b in the AES_CR register.

- Pad the last block smaller than 128 bits with zeros until reaching the size of 128 bits, then insert it as input to the AES.

- Upon completion, read the 128-bit generated data from the AES_DOUTR register and store it as intermediate data.

- Change the AES mode to GCM mode by writing the bitfield CHMOD[2:0] = 011b in the AES_CR register.

- Select Final phase by writing the bitfield GCMPH[1:0] = 11b in the AES_CR register.

- In the intermediate data, set to zero the bits corresponding to the padded bits of the last block of payload, then insert the resulting data as input to the AES.

- Upon completion, read the AES_DOUTR register. The data itself has no importance and can be ignored. This step is required to set up the internal state machine in a way for it to handle correctly the TAG generation during the GCM Final phase.

- Apply the normal Final phase as usual.

Although the reference manual indicates that mode changes should be avoided when the AES is enabled, the AES does not misbehave when this workaround is applied.

2.11 TIM

2.11.1 HSE/32 is not available for TIM16 input capture if RTC clock is disabled or other than HSE

Description

If the RTC clock is either disabled or other than HSE, the HSE/32 clock is not available for TIM16 input capture even if selected (bitfield TI1_RMP[2:0] = 101 in the TIM16_OR1 register).

Workaround

Apply the following procedure:

1.   Enable the power controller clock (bit PWREN = 1 in the RCC_APB1ENR1 register).

2.   Disable the backup domain write protection (bit DBP = 0 in the PWR_CR1 register).

3.   Enable RTC clock and select HSE as clock source for RTC (bits RTCSEL[1:0] = 11 and bit RTCEN = 1 in the RCC_BDCR register).

4.   Select the HSE/32 as input capture source for TIM16 (bitfield TI1_RMP[2:0] = 101 in the TIM16_OR1 register).

Alternatively, use TIM17 that implements the same features as TIM16, and is not affected by the limitation described.

2.12   LPTIM

2.12.1   LPTIM1 outputs cannot be configured as open-drain

Description

LPTIM1 outputs are set in push-pull mode regardless of the configuration of corresponding GPIO outputs.

Workaround

None.

2.12.2   MCU may remain stuck in LPTIM interrupt when entering Stop mode

Description

This limitation occurs when disabling the low power timer (LPTIM).

When the firmware clears the LPTIM_CR.ENABLE bit within a small time window around one LPTIM interrupt occurrence, then the LPTIM interrupt signal used to wake up the MCU from Stop mode may be frozen in active state. Consequently, when trying to enter Stop mode, this limitation prevents the MCU from entering low power mode and the firmware remains stuck in the LPTIM interrupt routine.

This limitation applies to all Stop modes and to all instances of the LPTIM. Note that the occurrence of this issue is very low.

Workaround

In order to disable a low power timer (LPTIMx) peripheral, do not clear its ENABLE bit in its respective LPTIMx_CR register. Instead, reset the whole LPTIMx peripheral via the RCC controller by setting and resetting its respective LPTIMxRST bit in RCC_APByRSTRz register.

2.13 I2C

2.13.1 10-bit master mode: new transfer cannot be launched if first part of the address is not acknowledged by the slave

Description

An I^{2}C-bus master generates STOP condition upon non-acknowledge of I^{2}C address that it sends. This applies to 7-bit address as well as to each byte of 10-bit address.

When the MCU set as I^{2}C-bus master transmits a 10-bit address of which the first byte (5-bit header + 2 MSBs of the address + direction bit) is not acknowledged, the MCU duly generates STOP condition but it then cannot start any new I^{2}C-bus transfer. In this spurious state, the NACKF flag of the I2C_ISR register and the START bit of the I2C_CR2 register are both set, while the START bit should normally be cleared.

Workaround

In 10-bit-address master mode, if both NACKF flag and START bit get simultaneously set, proceed as follows:
1. Wait for the STOP condition detection (STOPF = 1 in I2C_ISR register).
2. Disable the I2C peripheral.
3. Wait for a minimum of three APB cycles.
4. Enable the I2C peripheral again.

2.13.2 Wrong behavior in Stop mode when wakeup from Stop mode is disabled in I2C

Description

With the MCU operating as slave or as master in multi-master topology, when wakeup from Stop mode is disabled in I2C (WUPEN = 0) and the MCU enters Stop mode while a transfer is ongoing on the bus, the following may occur:
1. BUSY flag is wrongly set when the MCU exits Stop mode. This prevents from initiating a transfer in master mode, as the START condition cannot be sent when BUSY is set.
2. If clock stretching is enabled (NOSTRETCH = 0), the SCL line is pulled low by I2C and the transfer stalled as long as the MCU remains in Stop mode.
   The occurrence of such condition depends on the timing configuration, peripheral clock frequency, and I^{2}C-bus frequency.

Workaround

Disable I2C (PE = 0) before entering Stop mode and re-enable it when back in Run mode.

2.13.3 Wrong data sampling when data setup time (t$_{SU;DAT}$) is shorter than one I2C kernel clock period

Description

The I^{2}C-bus specification and user manual specify a minimum data setup time (t$_{SU;DAT}$) as:
- 250 ns in Standard mode
- 100 ns in Fast mode
- 50 ns in Fast mode Plus

The MCU does not correctly sample the I^{2}C-bus SDA line when t$_{SU;DAT}$ is smaller than one I2C kernel clock (I^{2}C-bus peripheral clock) period: the previous SDA value is sampled instead of the current one. This can result in a wrong receipt of slave address, data byte, or acknowledge bit.

Workaround

Increase the I2C kernel clock frequency to get I2C kernel clock period within the transmitter minimum data setup time. Alternatively, increase transmitter's minimum data setup time.

2.13.4 Spurious bus error detection in master mode

Description

In master mode, a bus error can be detected spuriously, with the consequence of setting the BERR flag of the I2C_SR register and generating bus error interrupt if such interrupt is enabled. Detection of bus error has no effect on the I^{2}C-bus transfer in master mode and any such transfer continues normally.

Workaround

If a bus error interrupt is generated in master mode, the BERR flag must be cleared by software. No other action is required and the ongoing transfer can be handled normally.

2.13.5 Last-received byte loss in reload mode

Description

If in master receiver mode or slave receive mode with SBC = 1 the following conditions are all met:
- I^{2}C-bus stretching is enabled (NOSTRETCH = 0)
- RELOAD bit of the I2C_CR2 register is set
- NBYTES bitfield of the I2C_CR2 register is set to N greater than 1
- byte N is received on the I^{2}C-bus, raising the TCR flag
- N - 1 byte is not yet read out from the data register at the instant TCR is raised,

then the SCL line is pulled low (I^{2}C-bus clock stretching) and the transfer of the byte N from the shift register to the data register inhibited until the byte N-1 is read and NBYTES bitfield reloaded with a new value, the latter of which also clears the TCR flag. As a consequence, the software cannot get the byte N and use its content before setting the new value into the NBYTES field.

For I2C instances with independent clock, the last-received data is definitively lost (never transferred from the shift register to the data register) if the data N - 1 is read within four APB clock cycles preceding the receipt of the last data bit of byte N and thus the TCR flag raising. Refer to the product reference manual or datasheet for the I2C implementation table.

2.14 USART

2.14.1 nRTS is active while RE = 0 or UE = 0

Description

The nRTS line is driven low as soon as RTSE bit is set, even if the USART is disabled (UE = 0) or the receiver is disabled (RE = 0), that is, not ready to receive data.

Workaround

Upon setting the UE and RE bits, configure the I/O used for nRTS into alternate function.

2.15 LPUART

2.15.1 LPUART1 outputs cannot be configured as open-drain

Description

LPUART1 outputs are set in push-pull mode regardless of the configuration of corresponding GPIO outputs.

Workaround

None.

2.16 SPI

2.16.1 BSY bit may stay high at the end of data transfer in slave mode

Description

BSY flag may sporadically remain high at the end of a data transfer in slave mode. This occurs upon coincidence of internal CPU clock and external SCK clock provided by master.

In such an event, if the software only relies on BSY flag to detect the end of SPI slave data transaction (for example to enter low-power mode or to change data line direction in half-duplex bidirectional mode), the detection fails.

As a conclusion, the BSY flag is unreliable for detecting the end of data transactions.

Workaround

Depending on SPI operating mode, use the following means for detecting the end of transaction:

- When NSS hardware management is applied and NSS signal is provided by master, use NSS flag.
- In SPI receiving mode, use the corresponding RXNE event flag.
- In SPI transmit-only mode, use the BSY flag in conjunction with a timeout expiry event. Set the timeout such as to exceed the expected duration of the last data frame and start it upon TXE event that occurs with the second bit of the last data frame. The end of the transaction corresponds to either the BSY flag becoming low or the timeout expiry, whichever happens first.

Prefer one of the first two measures to the third as they are simpler and less constraining.

Alternatively, apply the following sequence to ensure reliable operation of the BSY flag in SPI transmit mode:

1. Write last data to data register
2. Poll the TXE flag until it becomes high, which occurs with the second bit of the data frame transfer
3. Disable SPI by clearing the SPE bit mandatorily before the end of the frame transfer
4. Poll the BSY bit until it becomes low, which signals the end of transfer

Note: *The alternative method can only be used with relatively fast CPU speeds versus relatively slow SPI clocks or/and long last data frames. The faster is the software execution, the shorter can be the duration of the last data frame.*

2.16.2 Wrong CRC in full-duplex mode handled by DMA with imbalanced setting of data counters

Description

When SPI is handled by DMA in full-duplex master or slave mode with CRC enabled, the CRC computation may temporarily freeze for the ongoing frame, which results in corrupted CRC.

This happens when the receive counter reaches zero upon the receipt of the CRC pattern (as the receive counter was set to a value greater, by CRC length, than the transmit counter). An internal signal dedicated to receive-only mode is left unduly pending. Consequently, the signal can cause the CRC computation to freeze during a next transaction in which DMA TXE event service is accidentally delayed (for example, due to DMA servicing a request from another channel).

Workaround

Apply one of the following measures prior to each full-duplex SPI transaction:

- Set the DMA transmission and reception data counters to equal values. Upon the transaction completion, read the CRC pattern out from RxFIFO separately by software.
- Reset the SPI peripheral via peripheral reset register.

2.17 SDMMC

2.17.1 MMC stream write of less than 7 bytes does not work correctly

Description

Stream write initiated with WRITE_DAT_UNTIL_STOP command (CMD20) does not define the amount of data bytes to store. The card keeps storing data coming in from the SDMMC host until it gets a valid STOP_TRANSMISSION (CMD12) command. The commands are streamed on a line separate from data line, with common clock line.

As the STOP_TRANSMISSION command is 48-bit long and due to the bus protocol, the STOP_TRANSMISSION command start bit must be advanced by 50 clocks with respect to the stop bit of the data bitstream.

Therefore, for small data chunks of up to 6 bytes, SDMMC hosts should normally operate such that, the start of the STOP_TRANSMISSION (CMD12) command streaming precedes the start of the data streaming.

The microcontrollers duly anticipate the STOP_TRANSMISSION command streaming start, with respect to the data bitstream end. WAITPEND (bit 9 of SDMMC_CMD register) must be set for this mechanism to operate.

However, a failure occurs in case of small data chunks of up to 6 bytes. Instead of starting the STOP_TRANSMISSION command 50 clocks ahead of the data bitstream stop bit, the SDMMC peripheral on STM32L496xx and STM32L4A6xx MCUs starts the command along with the first bit of the data bitstream. As the command is longer than the data, it ends a number of clocks behind the data that the STM32L496xx and STM32L4A6xx software intended to store onto the card by setting the DATALENGTH register. During the clocks in excess, the SDMMC peripheral keeps the data line in logical-one level.

As a consequence, the card intercepts more data and updates more memory locations than the number set in DATALENGTH. The spuriously updated locations of memory receive 0xFF values.

Workaround

Do not use stream write WRITE_DAT_UNTIL_STOP (CMD20) with a DATALENGTH less then 8 bytes.

Use set block length (SET_BLOCKLEN: CMD16) followed by single block write command (WRITE_BLOCK: CMD24) instead of stream write (CMD20) with desired block length.

2.18 bxCAN

2.18.1 bxCAN Time-triggered mode not supported

Description

The Time-triggered communication mode described in the reference manual is not supported, and so time stamp values are not available. TTCM bit must be kept cleared in the CAN_MCR register (Time-triggered communication mode disabled).

Workaround

None.

2.19 OTG_FS

2.19.1 Data FIFO gets corrupted if the write sequence to the Transmit FIFO is interleaved with other OTGFS register access

Description

When the OTG Full Speed cell is in Host or Device mode, interrupting the write sequence in the transmit FIFO by any access (Read or Write) to OTG registers will corrupt the next data written to the transmit FIFO.

Workaround

Ensure that the transmit FIFO write accesses cannot be interrupted by a procedure performing accesses to the USB cell registers.

3   Revision history

Table 5. Document revision history

Date	Revision	Changes
24-Feb-2016	1	Initial release.
05-Sep-2016	2	Added: – Section 2.1.2: PCPROP area within a single Flash memory page becomes unprotected at RDP change from level1 to level0, Section 2.4.2: Wrong ADC conversion results when delay between calibration and first conversion or between 2 consecutive conversions is too long, Section 2.5: LPTIM, Section 2.6: TIM16, Section 2.7: LPUART, Section 2.8: JTAG, Section 2.9.4: Master new transfer cannot be launched if first part of the 10-bit address is NOT Acknowledged by the slave., Section 2.10: TSC, Section 2.11: AES Modified: – Table 3: Summary of silicon limitation – Section 2.12.1: MMC stream write of less than 7 bytes does not work correctly
09-Jan-2017	3	Added: – Section 2.1.1: Dual bank boot not working in RDP level 1 when the boot in flash is selected by BOOT0 pin, Section 2.1.3: Data Cache might be corrupted during Flash Read While Write operation, Section 2.1.4: MSI frequency overshoot upon Stop mode exit, Section 2.1.5: Internal voltage reference corrupted upon Stop mode entry with temperature sensing enabled, Section 2.3.1: First nibble of data is not written after dummy phase, Section 2.3.2: Wrong data can be read in memory-mapped after an indirect mode operation Modified: – Table 4: Summary of silicon limitation – Applicability
01-Mar-2017	4	Added: – Section 2.1.7: PCPROP area within a single Flash memory page becomes unprotected at RDP change from level1 to level0, Section 2.9.5: START bit is not cleared when the address is not acknowledged by the slave device Modified: – Table 4: Summary of silicon limitation, – Section 2.1.4: MSI frequency overshoot upon Stop mode exit, Section 2.3.1: First nibble of data is not written after dummy phase

Table 5. Document revision history (continued)

Date	Revision	Changes
08-Jun-2017	5	Added: Section 2.1.8: Spurious Brown Out Reset after short Run sequence, Section 2.1.6: OPAMP output: VDDA overconsumption, Section 2.9.6: Last received byte can be lost when using Reload mode with NBYTES > 1, Section 2.14: OTG_FS, Section 2.5.2: MCU may remain stuck in LPTIM interrupt when entering Stop mode Modified: – cover page: replaced former "Silicon identification" with *Applicability*, and former table Device identification with *Table 2: Device variants*. – Table 4: Summary of silicon limitation, Section 2: STM32L496xx STM32L4A6xx silicon limitations
20-Dec-2017	6	Added: – *Section 2.3.1: Code segment unprotected if non-volatile data segment length is zero* and *Section 2.3.2: Code and non-volatile data unprotected upon bank swap* Removed: – the limitation "START bit is not cleared when the address is not acknowledged by the slave device", as describing the same limitation as *Section 2.13.1* Modified: – the structure of the document – move of core limitation to *Section 2: Description of device limitations* – section TIM16 renamed in *TIM* – reference manual (RM0351) associated with this document – alignment of the order of limitations with the reference manual – limitation descriptors in *Section 2.13: I2C*
16-Feb-2018	7	Added: – *Section 2.1.2: VDIV or VSQRT instructions might not complete correctly when very short ISRs are used* – *Section 2.1.3: Store immediate overlapping exception return operation might vector to incorrect interrupt* – *Section 2.7.1: Spurious temperature measurement due to spike noise* – *Section 2.16.1: BSY bit may stay high at the end of data transfer in slave mode* – *Section 2.16.2: Wrong CRC in full-duplex mode handled by DMA with imbalanced setting of data counters* – third-party logo in *Section 2: Description of device limitations*

Table 5. Document revision history (continued)

Date	Revision	Changes
16-Feb-2018	7 (continued)	Removed: – former section 2.2.7., as duplicating *Section 2.2.2: PCPROP area within a single Flash memory page becomes unprotected at RDP change from Level 1 to Level 0* Modified: – *Section 2.1.1: Interrupted loads to SP can cause erroneous behavior* aligned with Arm's description – *Section 2.2.4: MSI frequency overshoot upon Stop mode exit* – *Section 2.3.2: Code and non-volatile data unprotected upon bank swap* – minor modifications (language, style or simplification) in some other sections – Document identification number in the page footers, from DocID026121 to ES0335

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